#### DISCRETE SEMICONDUCTORS

## DATA SHEET

# BTA212 series B Three quadrant triacs high commutation

**Product specification** 

September 2018



### Three quadrant triacs high commutation

#### BTA212 series B

#### **GENERAL DESCRIPTION**

Glass passivated high commutation triacs in a plastic envelope intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. These devices will commutate the full rated rms current at the maximum rated junction temperature, without the aid of a snubber.

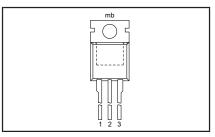
#### **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX.	MAX.	MAX.	UNIT
$V_{DRM}$	BTA212- Repetitive peak off-state	<b>500B</b> 500	<b>600B</b> 600	<b>800B</b> 800	V
I <sub>T(RMS)</sub> I <sub>TSM</sub>	voltages RMS on-state current Non-repetitive peak on-state current	12 95	12 95	12 95	A A

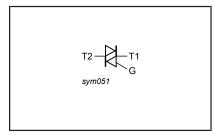
#### **PINNING - TO220AB**

PIN	N DESCRIPTION		
1	main terminal 1		
2	main terminal 2		
3	gate		
tab	main terminal 2		

#### PIN CONFIGURATION



#### **SYMBOL**



#### **LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.		MAX.		UNIT
$V_{DRM}$	Repetitive peak off-state voltages		-	<b>-500</b> 500 <sup>1</sup>	<b>-600</b> 600 <sup>1</sup>	<b>-800</b> 800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave;	-		12		A
I <sub>TSM</sub>	Non-repetitive peak on-state current	$T_{mb} \le 99 ^{\circ}\text{C}$ full sine wave; $T_{j} = 25 ^{\circ}\text{C}$ prior to surge t = 20 ms	-		95		A
l²t dl <sub>⊤</sub> /dt	I <sup>2</sup> t for fusing Repetitive rate of rise of on-state current after triggering	$\begin{array}{l} t = 16.7 \text{ ms} \\ t = 10 \text{ ms} \\ I_{TM} = 20 \text{ A}; \ I_{G} = 0.2 \text{ A}; \\ dI_{G}/dt = 0.2 \text{ A}/\mu\text{s} \end{array}$	-		105 45 100		Α A²s A/μs
I <sub>GM</sub> V <sub>GM</sub> P <sub>GM</sub> P <sub>G(AV)</sub>	Peak gate current Peak gate voltage Peak gate power Average gate power	over any 20 ms period	- - -		2 5 5 0.5		A V W W
T <sub>stg</sub>	Storage temperature Operating junction temperature	period	-40 -		150 125		ů. Ĉ

September 2018 1 Rev 1.300

<sup>1</sup> Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15  $A/\mu s$ .

WeEn Semiconductors Product specification

## Three quadrant triacs high commutation

BTA212 series B

#### THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R <sub>th i-a</sub>	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle in free air		- - 60	1.5 2.0 -	K/W K/W K/W

#### STATIC CHARACTERISTICS

T<sub>i</sub> = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I <sub>GT</sub>	Gate trigger current <sup>2</sup>	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$				
		T2+ G+	2	18	50	mA
		T2+ G-	2	21	50	mA
		T2- G-	2	34	50	mA
l IL	Latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$				
		T2+ G+	-	31	60	mA
		T2+ G-	-	34	90	mA
		T2- G-	-	30	60	mA
I <sub>H</sub>	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	-	31	60	mA
$V_{T}^{I_{H}}$	On-state voltage	$I_T = 17 \text{ A}$	-	1.3	1.6	V
V <sub>GT</sub>	Gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$	-	0.7	1.5	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_L = 125 \text{ °C}$	0.25	0.4	-	V
$I_{D}$	Off-state leakage current	$V_D = V_{DRM(max)}$ ; $T_j = 125  ^{\circ}C$	-	0.1	0.5	mA

#### **DYNAMIC CHARACTERISTICS**

 $T_i = 25$  °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV <sub>D</sub> /dt	Critical rate of rise of	$V_{DM} = 67\% V_{DRM(max)}; T_j = 125 °C;$	1000	4000	-	V/μs
dI <sub>com</sub> /dt	off-state voltage Critical rate of change of commutating current	exponential waveform; gate open circuit $V_{DM} = 400 \text{ V}$ ; $T_j = 125 ^{\circ}\text{C}$ ; $I_{T(RMS)} = 12 \text{ A}$ ; without snubber; gate open circuit	-	24	-	A/ms
$t_{gt}$	Gate controlled turn-on time	$I_{TM} = 12 \text{ A}$ ; $V_D = V_{DRM(max)}$ ; $I_G = 0.1 \text{ A}$ ; $dI_G/dt = 5 \text{ A}/\mu \text{s}$	-	2	-	μs

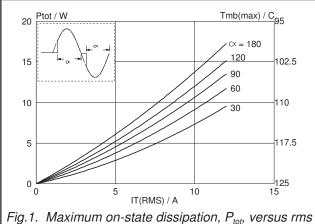
September 2018 2 Rev 1.300

<sup>2</sup> Device does not trigger in the T2-, G+ quadrant.

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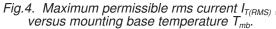
#### Three quadrant triacs high commutation

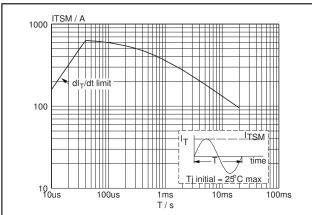
#### BTA212 series B



IT(RMS) / A 99°C 10 5 50 Tmb / C 100 150 Fig.4. Maximum permissible rms current  $I_{T(RMS)}$ ,

Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus rms on-state current,  $I_{T(RMS)}$ , where  $\alpha$  = conduction angle.





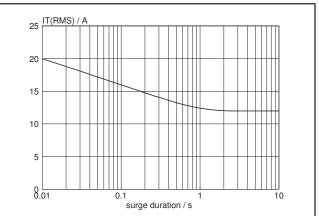
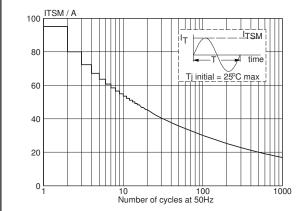


Fig.2. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \le 20$ ms.

Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents, f = 50 Hz;  $T_{mb} \le 99$ °C.



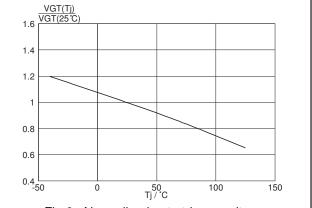
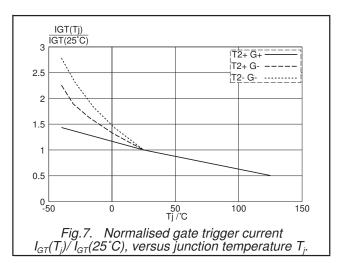


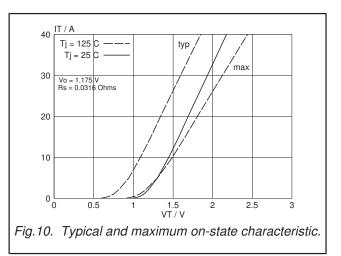
Fig.3. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus number of cycles, for sinusoidal currents, f = 50 Hz.

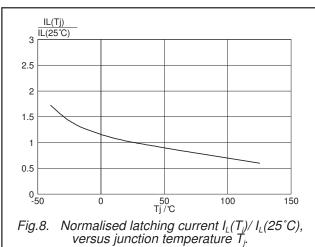
Fig.6. Normalised gate trigger voltage  $V_{GT}(T_i)/V_{GT}(25^{\circ}C)$ , versus junction temperature  $T_i$  WeEn Semiconductors Product specification

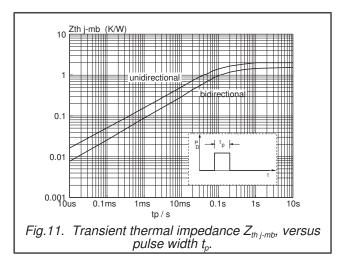
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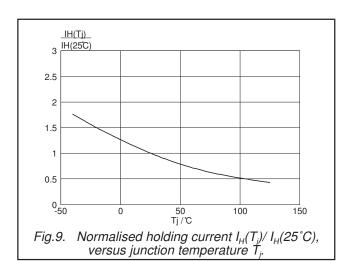
#### BTA212 series B

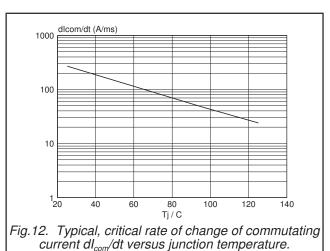










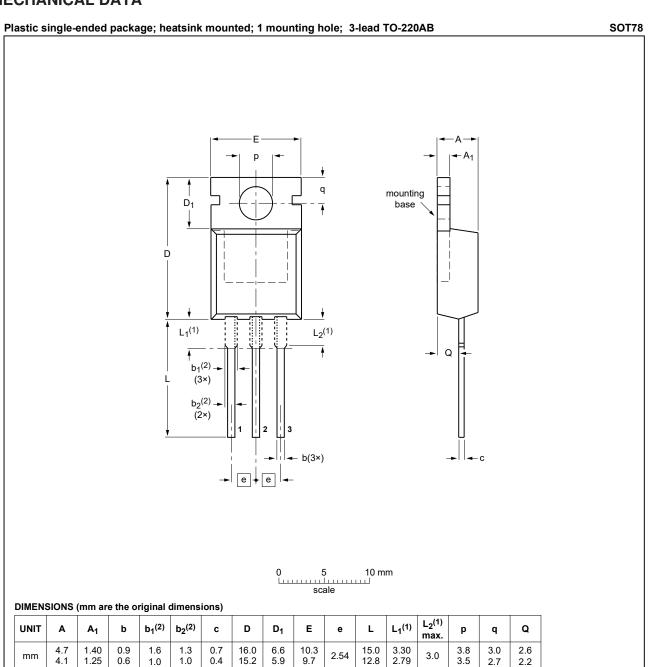


WeEn Semiconductors Product specification

## Three quadrant triacs high commutation

BTA212 series B

#### **MECHANICAL DATA**



#### Notes

- 1. Lead shoulder designs may vary.
- 2. Dimension includes excess dambar.

OUTLINE		REFER	ENCES		EUROPEAN ISSUE DAT		EUROPEAN ISSUE DAT	
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE		
SOT78		3-lead TO-220AB	SC-46			<del>08-04-23</del> 08-06-13		

#### Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
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